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... Minimum **dc** power at a given output power and ... the strain [69] and the **high**-permittivity gate ... The **frequency** requires additional assumptions for ef- fective gate ...

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... its advantages in bandwidth (optical carrier **frequency** 100 THz ... current [3]. **Thresholds** below 1 mA and **high** ... **high** speed optical interconnects up to the LAN level ...

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H Yu, L He - ... TRANSACTIONS ON COMPUTER-AIDED DESIGN OF INTEGRATED **CIRCUITS** ..., 2005 - [ieeexplore.ieee.org](http://ieeexplore.ieee.org)

... Therefore, it has a **high** accuracy only for a few number of filaments ... be stamped in the MNA matrix with the correct **dc** information in both **frequency** and time ...

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### CMOS Circuit Design

B Telemetry - [phd.dtv.dk](http://phd.dtv.dk)

... af RF signalet til **DC**, over- spændingsbeskyttelse ... often used in CMOS bandgap references and bias **circuits**. ... especially with respect to **high-frequency** losses in ...

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### Design guidelines for assessing and controlling spacecraft charging effects

CK PURVIS, HB GARRETT, AC WHITTLESEY, NJ STEVENS - 1984 - [snebulos.mit.edu](http://snebulos.mit.edu)

... signal charac- teristics, and **frequency** of electrostatic ... solar arrays in which the **high** secondary yield ... a resistance-inductance-capacitance (**RLC**)series circuit ...

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S Administration - [ntrs.nasa.gov](http://ntrs.nasa.gov)

... Figure 4. **Frequency** response of roll angle to roll ... Furthermore, the **high-fidelity simulation** is used to ... Biomedical Results from Skylab, Washington, **DC**, NASA SP ...

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IEEE CNF IEEE Conference Proceeding

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Ohta, M.; Koizumi, T.;  
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Volume 57, Issue 6, June 1969 Page(s):1231 - 1232  
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- ☐ **14. A complete simulator architecture for inter-vehicle communication based warning systems**  
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- ☐ **16. Minimum Classification Error Interactive Training for Speaker Identification**  
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IEEE STD IEEE Standard

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IEE JNL IEE Journal or Magazine

IEEE CNF IEEE Conference Proceeding

IEE CNF IEE Conference Proceeding

IEEE STD IEEE Standard

- ☐
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- 
- Hall, S. H.; Hall, G. W.; McCall, J. A.;
- 
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3	BRS	L3	1036	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (threshold\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
4	BRS	L4	1	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (threshold\$) and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:15
5	BRS	L5	1	(simulation and (high adj frequency)) and (circuits same (high adj frequency)) and (thresholds) and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:16
6	BRS	L6	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
7	BRS	L7	40	(simulation same substrates) and (thresholds same integration)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
8	BRS	L8	4	(simulation same substrates) and (thresholds same integration) and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18

	Type	L #	Hits	Search Text	DBs	Time Stamp
9	BRS	L9	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wires\$	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:18
10	BRS	L10	2	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:19
11	BRS	L11	1	(simulation same substrates) and (thresholds same integration) and (high adj frequency) and wire\$ and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:22
12	BRS	L12	2	"6925430".pn.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
13	BRS	L14	0	(substrate and (simulation or model) and (high adj frequency)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:26
14	BRS	L13	224	(substrate and (simulation or model)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28
15	BRS	L15	100	(substrate and (simulation)).ti.	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28
16	BRS	L16	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:28

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17	BRS	L17	4	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
18	BRS	L18	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and wires and resitance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
19	BRS	L19	0	(substrate and (simulation)).ti. and substrate and simulation and circuits and threshold	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:29
20	BRS	L20	18	(substrate and (simulation)).ti. and substrate and simulation and circuits	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:31
21	BRS	L21	1	(simulation same (wiring near pattern)) and thresholds and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:32
22	BRS	L22	560	(first adj threshold) and (second adj threshold) and wiring and circuits	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
23	BRS	L23	0	(first adj threshold) and (second adj threshold) and wiring and circuits and (resitance same calculation)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
24	BRS	L24	0	(first adj threshold) and (second adj threshold) and wiring and circuits and (resitance near calculation)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40

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25	BRS	L25	0	(first adj threshold) and (second adj threshold) and wiring and circuits and resitance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:40
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27	BRS	L27	11	(first adj threshold) and (second adj threshold) and wiring and circuits and skin	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:41
28	BRS	L28	0	(first adj threshold) and (second adj threshold) and wiring and (skin adj resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
29	BRS	L29	0	(first adj threshold) and (second adj threshold) and wiring and (skin near resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
30	BRS	L30	308	(first adj threshold) and (second adj threshold) and wiring and (resistance\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
31	BRS	L31	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and calulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:42
32	BRS	L32	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43



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33	BRS	L33	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:43
34	BRS	L34	173	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and substrates	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
35	BRS	L35	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and elementsa	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
36	BRS	L36	249	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and elements	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:44
37	BRS	L37	8	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and (elements near plurality)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:00
38	BRS	L38	0	(first adj threshold) and (second adj threshold) and wiring and (resistance\$) and (elements near plurality) and (high adj frequency)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 10:47
39	BRS	L39	15	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:01
40	BRS	L40	4	(first adj threshold) and (second adj threshold) and wiring and (resistance\$ same calcu\$) and simulation	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:12

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43	BRS	L43	2	716/5.ccls. and (first adj threshold) and (second adj threshold) and resistance	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
44	BRS	L44	0	716/5.ccls. and (DC adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:15
45	BRS	L45	0	716/5.ccls. and (skin adj resitance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16
46	BRS	L46	11	716/5.ccls. and ((move or sort or arrange) same resistance)	USPAT; EPO; JPO; DERWEN T; IBM_TDB	2006/01/26 11:16

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